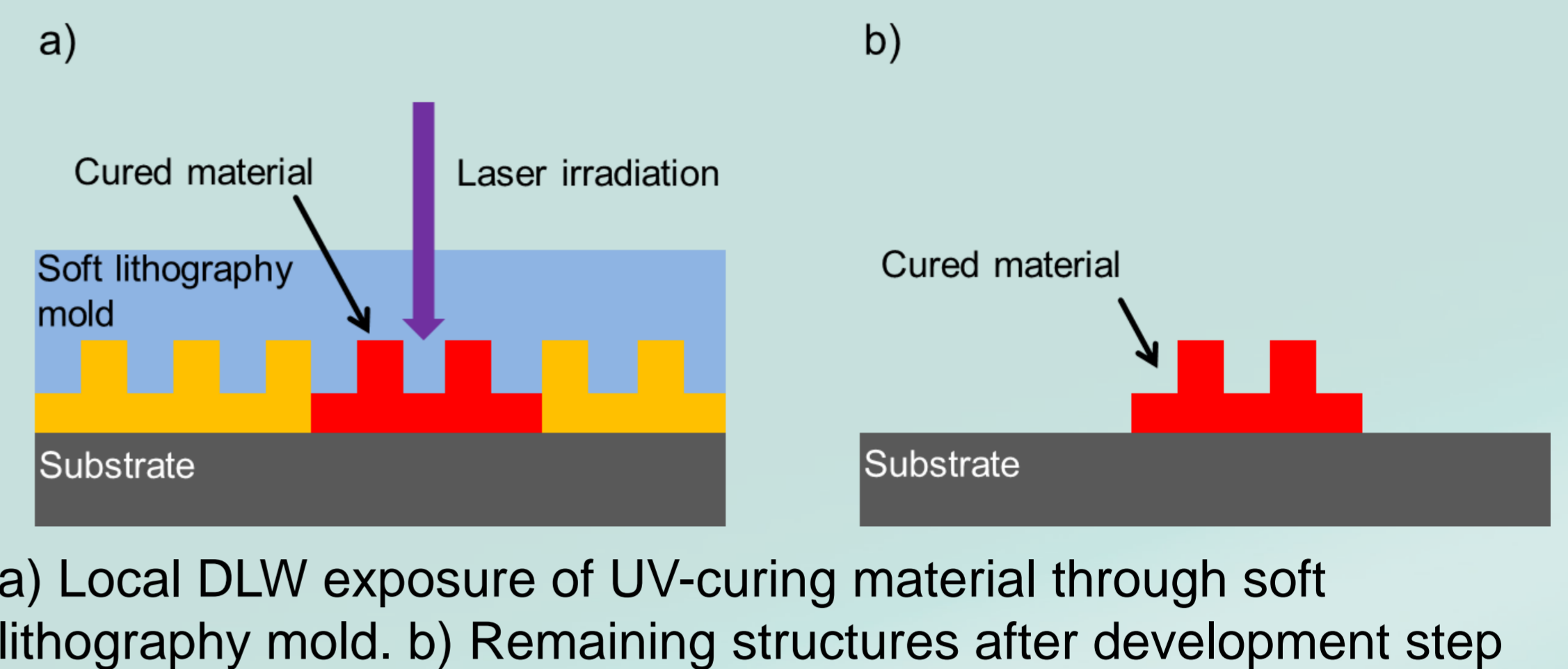


Introduction and process scheme

- The fabrication of combined nano- and micropatterns is of interest for different application fields (e.g. photonics, microfluidics) [1,2].
- We present a novel approach based on the combination of direct laser writing (DLW) and soft lithography molds.
- Results concerning the fabrication of hierarchical structures and local structure transfer into imprint resists ("local" imprinting) are presented.

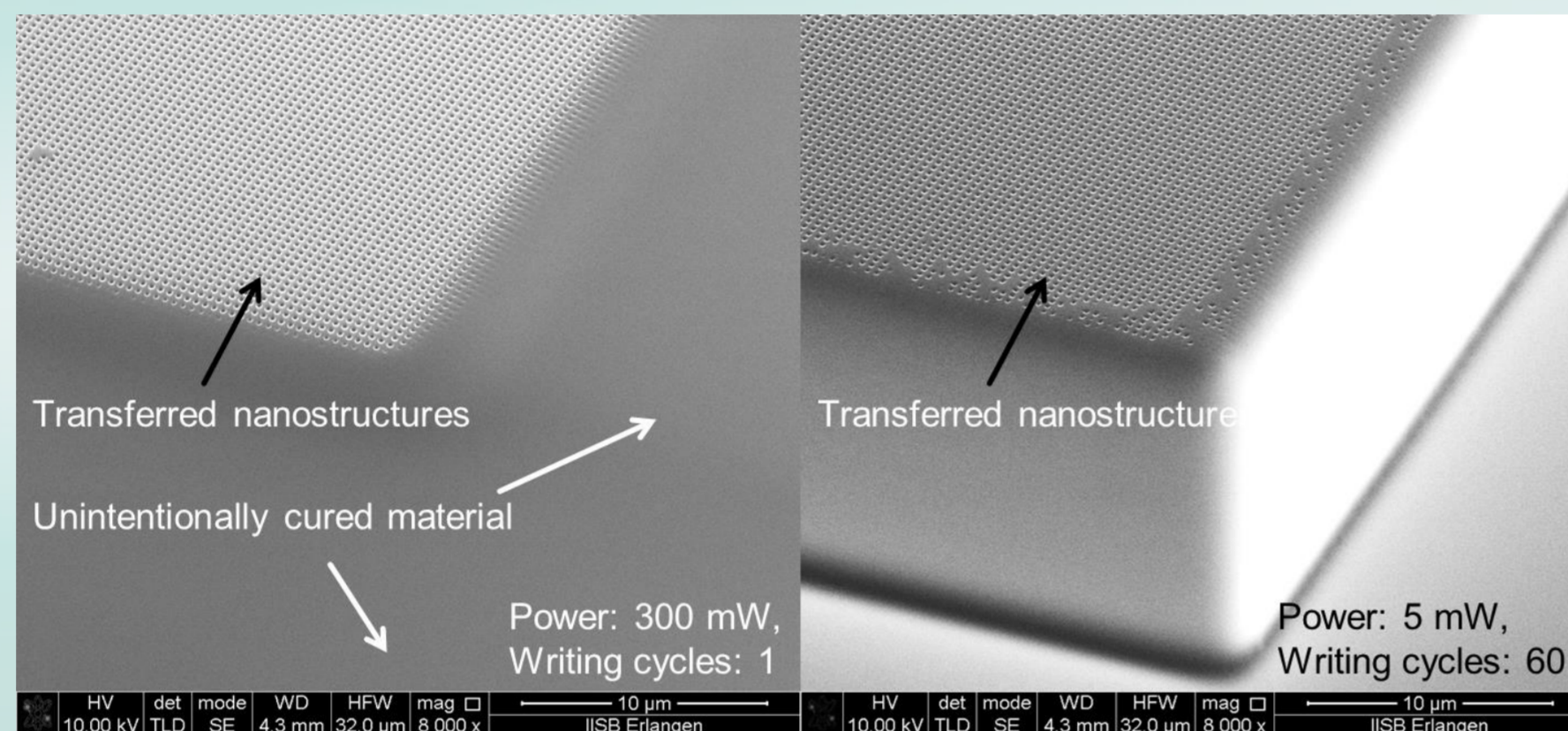


Fabrication of hierarchical structures

Experiments on silicon

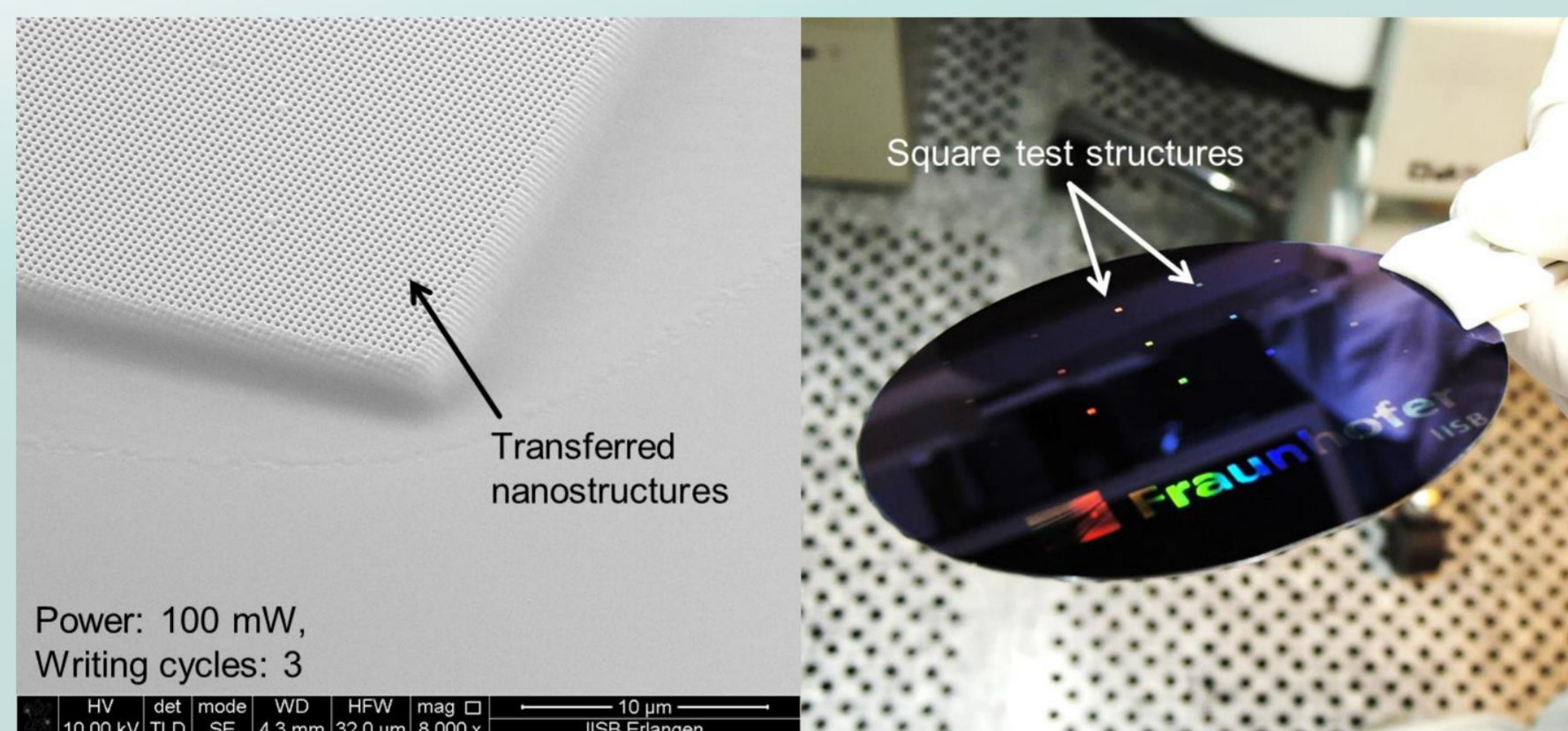
Impact of exposure parameters

- Crucial impact of laser power on sidewall formation
- Uncontrollable curing outside irradiated area for high exposure power
- Multi-cycle exposure renders nearly vertical sidewalls



Use of diluted OrmoComp[®]

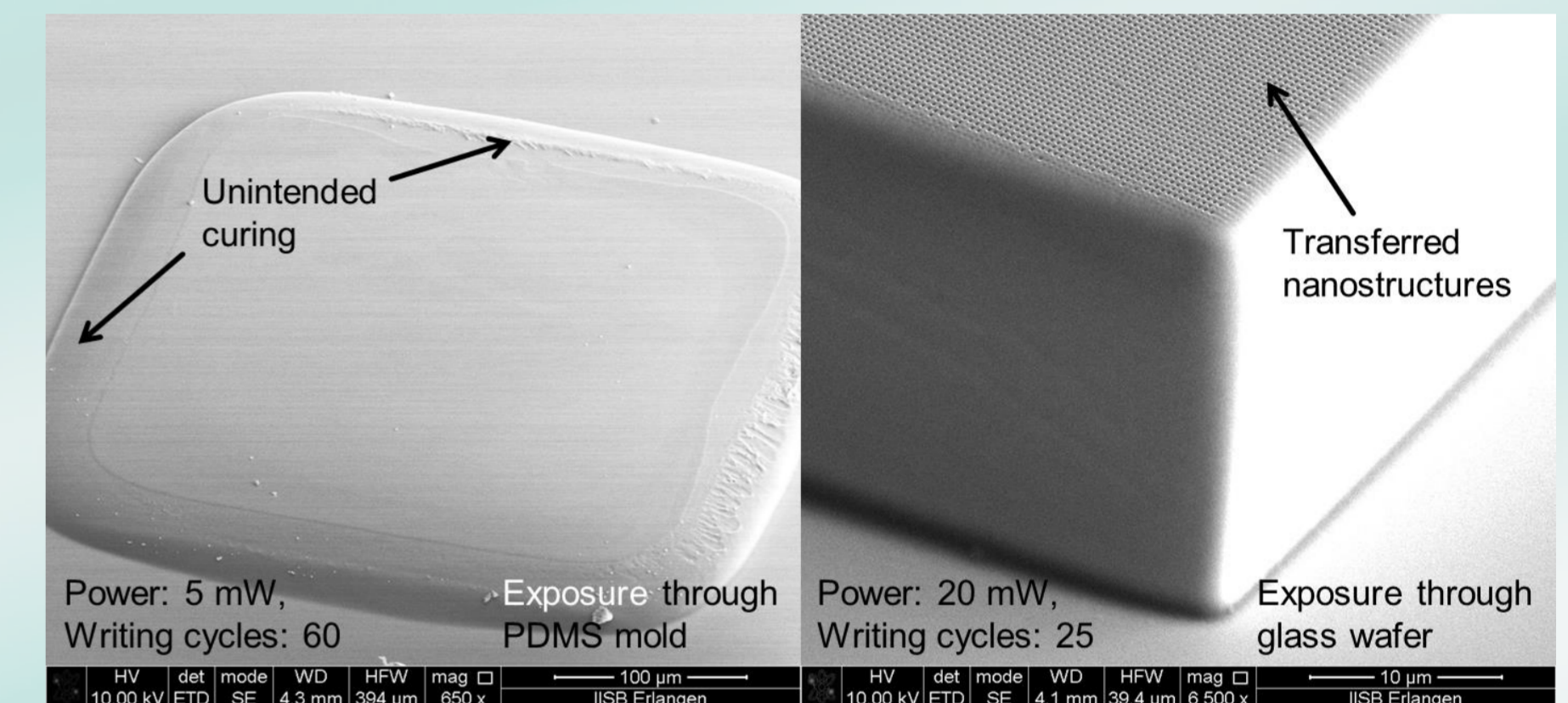
- Dilution of OrmoComp[®] with PGMEA (ratio 1:1)
- Unwanted curing reduced, UV-sensitivity decreased?
- Enables reduction of process time



Experiments on glass

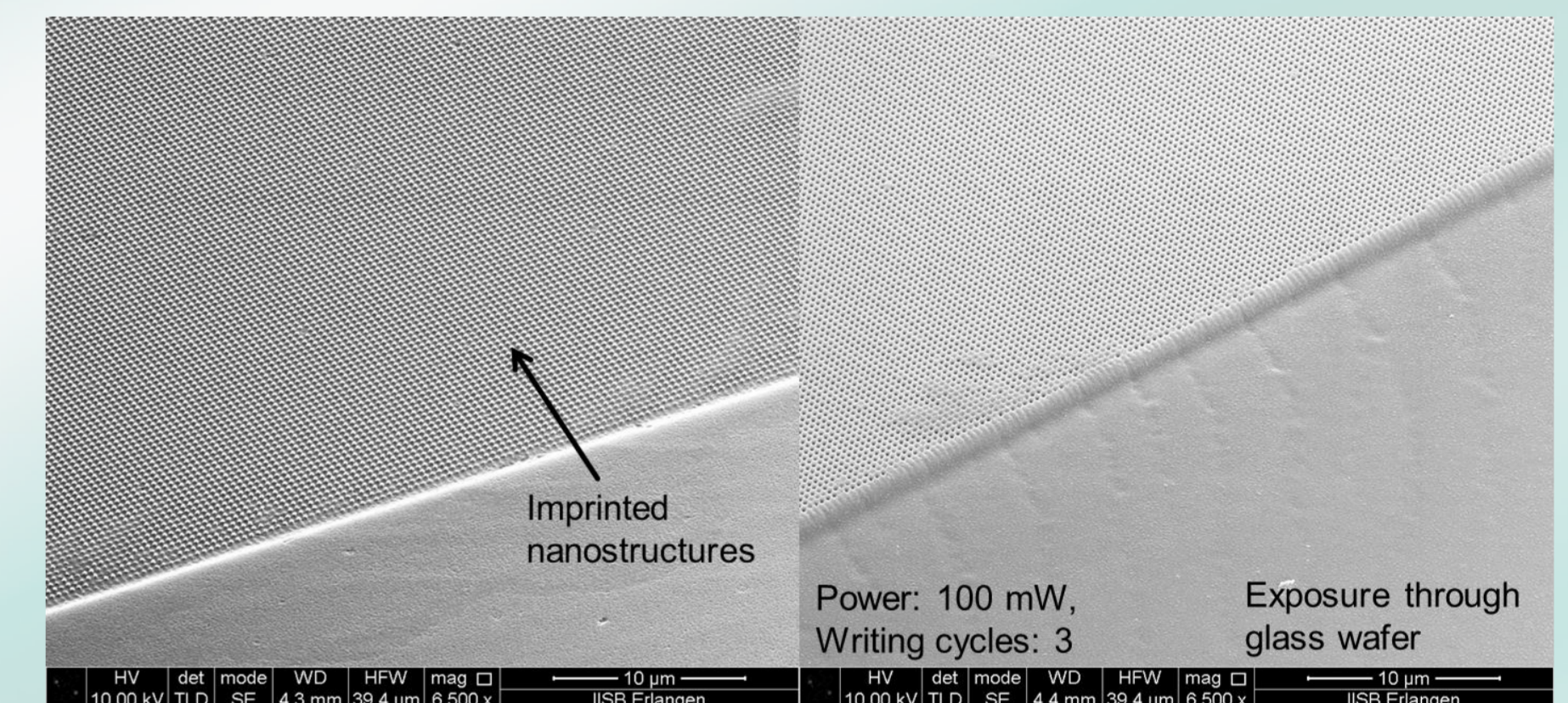
Influence of mold-structures

- No 1:1 transfer of parameters from Si-process possible
- Coupling of laser light into glass wafer due to diffraction effects?
- Exposure through glass wafer excludes influence of mold structures



Hierarchical structure as UV-NIL mold

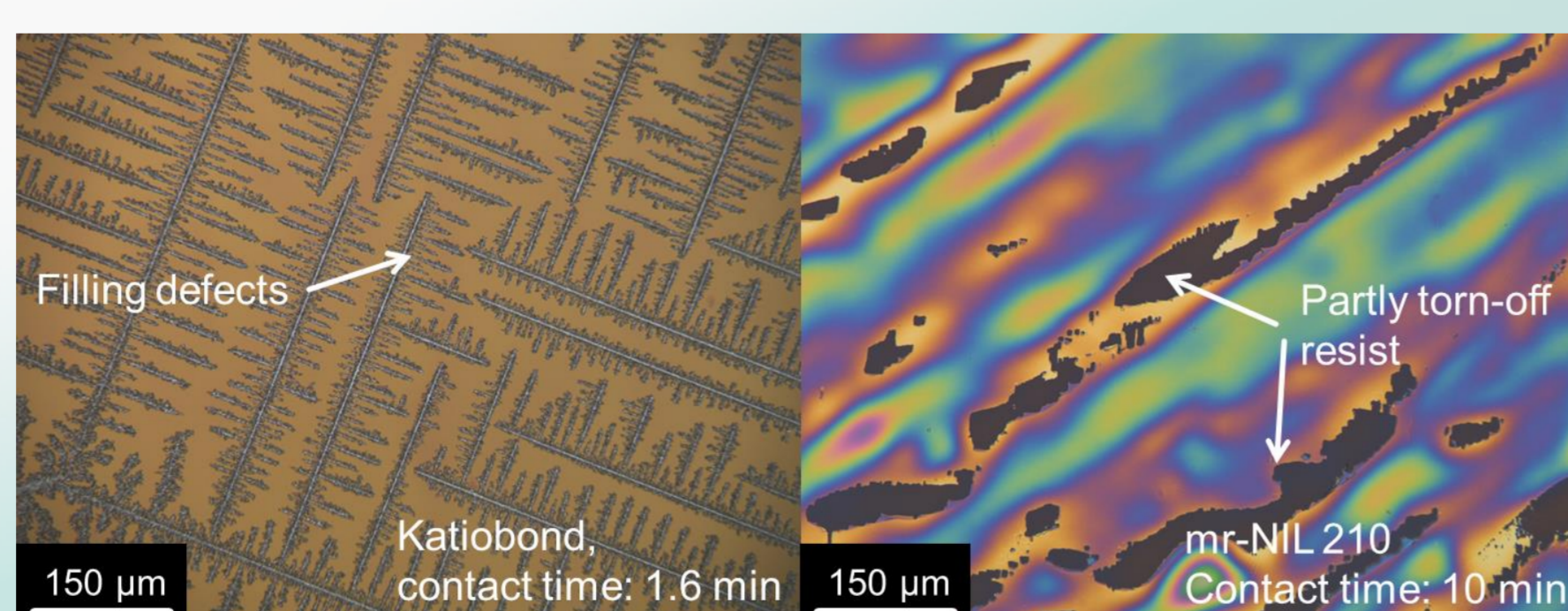
- Manual test imprint using hierarchical structure fabricated by DLW through PDMS mold
- Successful replication of nanostructures



"Local" imprinting

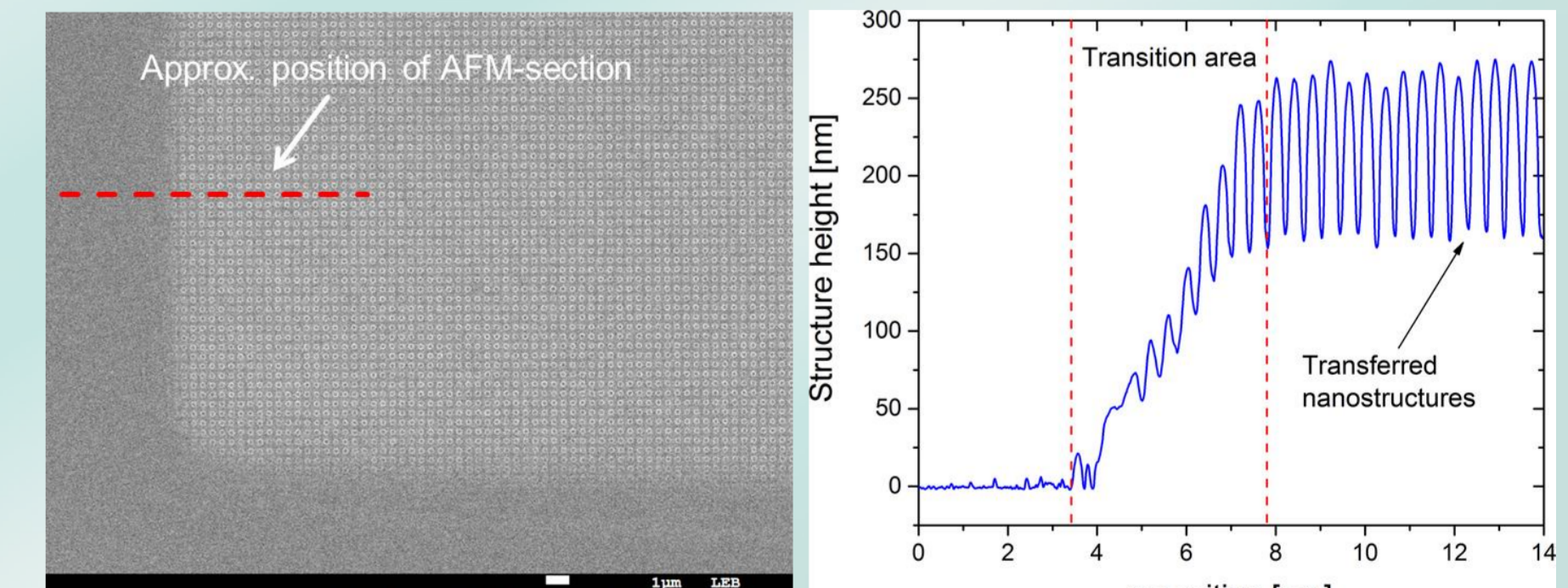
Resist diffusion into PDMS

- Evaluation of diffusion behavior of Katiobond 110707 and mr-NIL210 [3,4]
- No stable condition for both resists → PDMS mold unusable
- Use of "hybrid" PDMS/OrmoComp[®]-molds



Exposure through „hybrid“ mold

- Successful local transfer of nanostructures into mr-NIL210
- Formation of transition area with incomplete resist removal
- Further process optimization necessary



Conclusions

- A novel approach for the combined fabrication of nano- and microstructures is presented.
- Fabrication of hierarchical structures and "local" imprinting successfully demonstrated

Outlook

- Optimization of exposure parameters for "local" imprinting (reduction of transition area and residual layer thickness)
- Combination of nanostructures from different molds on one substrate

[1] Liao, Y. et al., Lab Chip 12, 746-9 (2012).

[2] Warren-Smith, S. C., Opt. Express 24, 378-87 (2016).

[3] Fader, R. et al., Microelectron. Eng. 98, 238-41 (2012).

[4] Schlachter, F. et al., Microelectron. Eng. 155, 118-21 (2016).